# After 30 Years Why Are We Still Talking about Known Good Die?

TRACK INNOVATION

IDENTIFY TRENDS

ANALYZE GROWTH

INFLUENCE DECISIONS

E. Jan Vardaman,

**President and Founder** 

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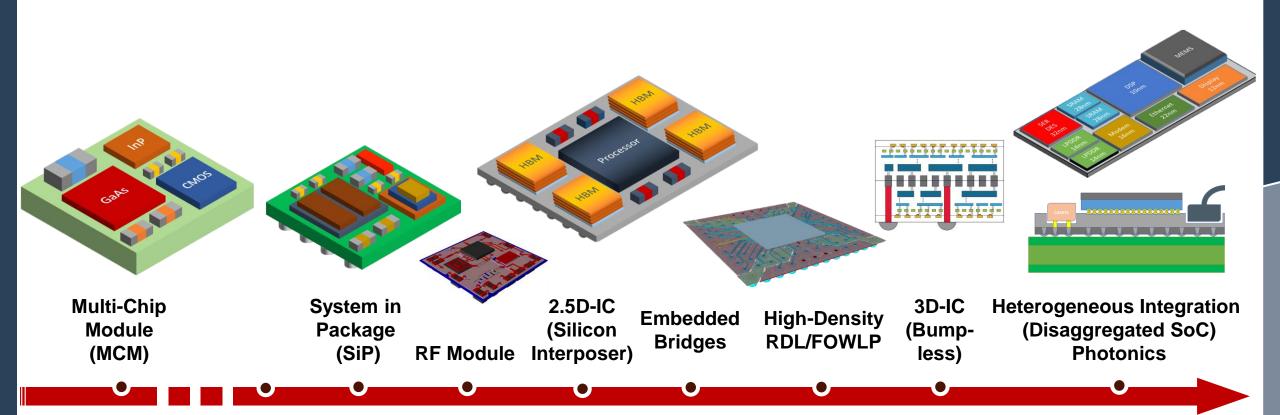


#### Multichip Modules (MCMs)

- Survey results of merchant MCM vendors from 1993
  - Single most important barrier to MCM use was the availability of affordable know good die (KGD)
  - Majority of bare die sold processed through parametric or continuity electrical testing
  - Problem: small, but significant number of ICs that passed parametric testing have latent defects that do not show up until being in operation for some time
  - Low module yield that increased the cost of repair and rework was one of the greatest concerns
- Vertically integrated companies had some advantages (they could use their internally fabricated die)



# **Evolution of Advanced Multi-Chip(let) Packaging Technologies**



1980 199099820052010201420162018 Now

cadence

Source: Cadence Design Systems.



#### A New 3D Era is Emerging

- A new era in 3D will provide advantages to optimize system power, performance, area, and cost
  - It is possible to continue scaling, but cost advantages are achieved with advanced packaging innovations
- Potential solutions for high-performance packaging (partition the die)
  - Homogeneous integration (split die to reduce die size and improve yield at wafer level)
  - Heterogeneous integration (interposers, FO-on-substrate or other multi-die solutions such as "chiplets," and some variation of 3D stacking)
  - Introduction of 3D chip stacking with bumpless bonding
- Heterogeneous integration provides a solution that can be in many formats!
  - Silicon interposers (called 2.5D but HIR refers to this as 2DS)
  - Alternatives such as Intel's EMIB or Fan-out on Substrate or Organics (2DO)
  - "Chiplets" where substrate interconnect provides in package communication between different functions
  - 3D structures with TSVs or direct bond interconnect



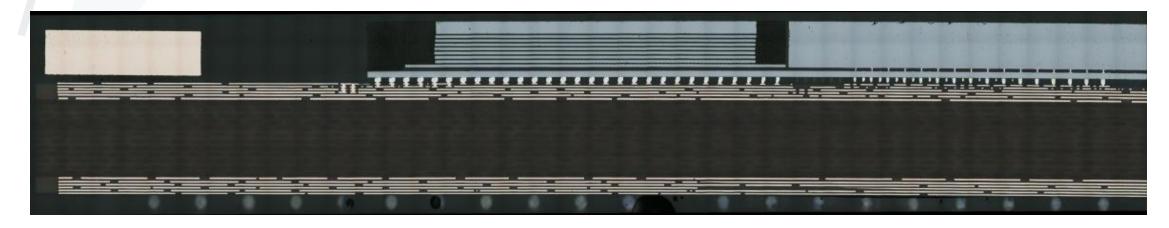
# **Challenges for Heterogeneous Integration**

- Requires new architectures and co-design
  - EDA tools required
  - Need good thermal and electrical modeling
- Large body sizes = large laminate substrate body sizes (some request for future 100 mm x 100 mm) make board-level assembly difficult
  - Warpage changes during reflow
- Thermal challenges
  - Need new designs with lower power dissipation
  - Need new thermal interface materials and cooling methods
- Test Challenges
  - Known Good Die (KGD)
  - Need more comprehensive test content that can be run at wafer-level
  - Need new methods to probe fine pitch bumps or test coverage without touching μbumps





#### **NVIDIA's GPU + HBM**



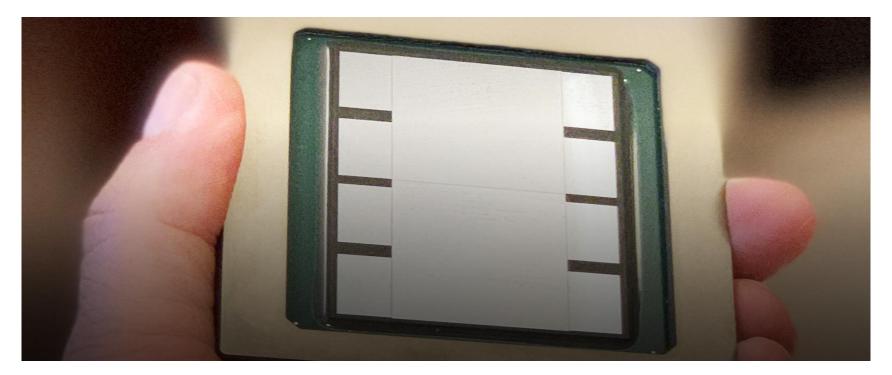
- NVIDIA's GPU with 4 HBMs (8 high stack + logic layer) mounted on Si interposer
  - HBM with wide bus (1,024 I/Os, ~4,000 bumps, 55μm micro bump pitch)
  - Silicon interposer is 34 mm x 43 mm with
     1.1μm lines and 1.6μm space
- NVIDIA's latest A100 uses GPU + 6 HBMs
- HBM cost ~\$200 each, Si interposer
   \$1,000+, expensive solution requires high reliability,



Source: NVIDIA.



#### **TSMC CoWoS**



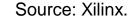
Source: TSMC.

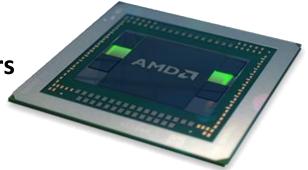
- Largest silicon interposer from TSMC in production is 2,500 mm<sup>2</sup>
  - >2X reticle size
- Room for two, 600mm<sup>2</sup> processors + 8 HBMs in 75mm x 75mm package

# Early Examples with Si Interposers: What Have We Learned

- FPGA shipments started (HVM 2012)
  - Xilinx has many products
  - Partition die so that the large die can me fabricated into "slices' providing better yield, improved performance

- Binning die provided a big advantage
- ASIC designs moving into production
- GPU + stacked memory
  - Provide higher performance for applications such as gaming
  - Memory stack + logic
- Applications expanded to include network systems, AI accelerators for datacenters, servers

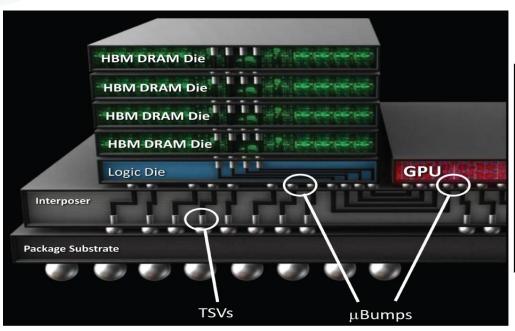


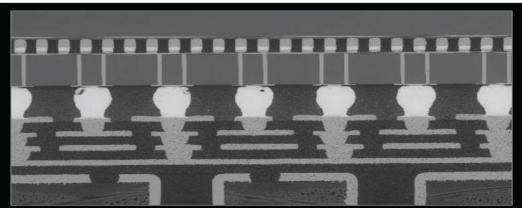


Source: AMD.



## AMD's "Fiji" with Silicon Interposer and HBM





Source: AMD.

- AMD "Fiji" solution for the graphics market
- Four HBM stacks, each containing stacked DRAMs and a logic die with TSVs mounted on a 1,011mm<sup>2</sup> Si interposer



#### **Test Strategy: Key To AMD Success**

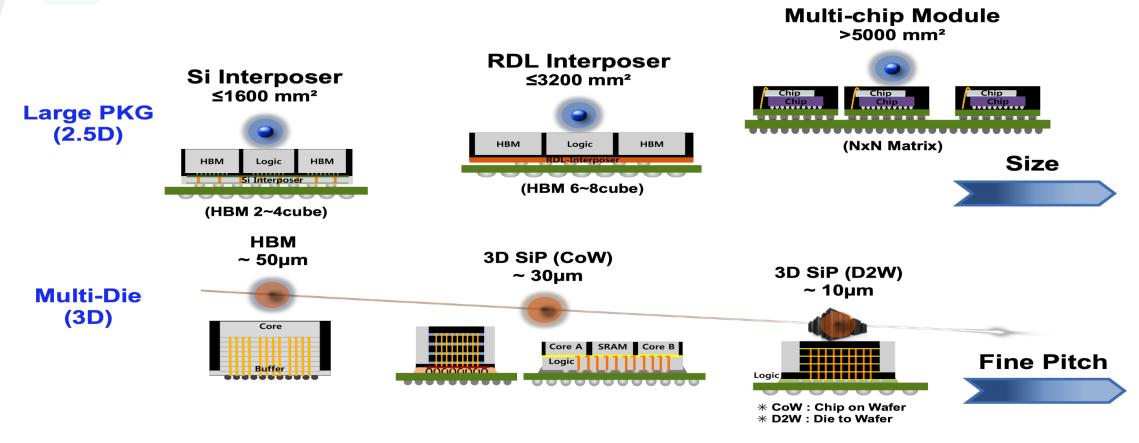


Source: ASE and AMD.

- Wafer sort, binning
- Partial assembly test (unique to this application, LGA pad surface finish, contact force control, yield repeatability, and contamination control)
- Final test



# Samsung's Package Integration Solutions for AI/Server/HPC



Source: Samsung.

 Samsung offers multiple solutions for high-performance applications and has an advantage in supply of HBM with its own internal production

## **HBM Development**

#### Stacked die with TSVs requirements

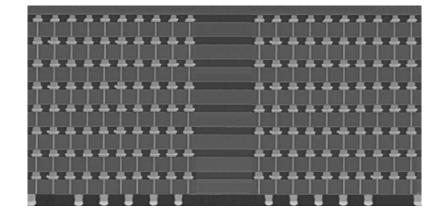
- Well joined TSV/micro bumps
- Well aligned micro bumps
- No underfill delamination or voids

#### Test vehicles TSV stacked memory

- Robustness of TSVs and micro bumps important
- All test patterns electrically tested in test vehicles

#### Key factors in success

- BIST
- Redundancy

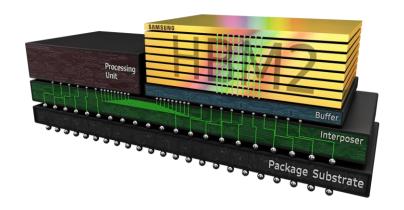




#### **High Bandwidth Memory**

#### Advantages

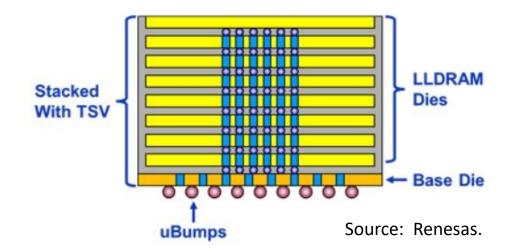
- Higher bandwidth
- Lower latency
- Lower power consumption
- Micro bumps used to connect die
- Suppliers
  - Samsung (HBM)
  - SK Hynix (HBM)
  - Micron (future HBM)
  - Renesas (Low-latency HBM)



Source: Samsung.



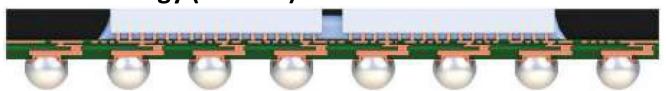
Source: Chipworks.





#### Fan-out on Substrate: Future Use with HBM

- ASE's Fan-Out Chip on Substrate (FOCoS)
  - RDL with  $2/2\mu m$  L/S
  - Up to 3 RDLs plus UBM
  - High I/O (>1,000)
  - Production with chip first since 2016 (Hi-Silicon Network Switch)
  - Chip last qualified
- TSMC Integrated Fan-Out on Substrate (InFO\_oS) and InFO\_MS
  - RDL with 2/2 $\mu$ m L/S
  - Up to 3 RDLs plus UBM
  - Production of InFO\_oS (MediaTek Network Switch)
- Amkor's Silicon Wafer Integrated Fan-out Technology (SWIFT®)
  - RDL with 2/2 $\mu$ m L/S
  - Up to 3 RDLs plus UBM



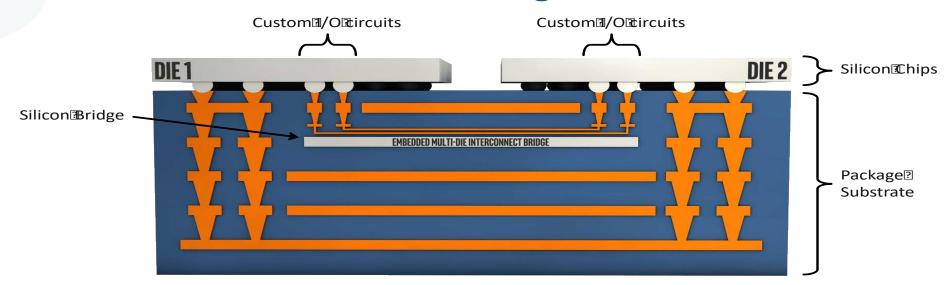


FOCoS – Fan Out Chip on Substrate (FO FCBGA)

Source: ASE.

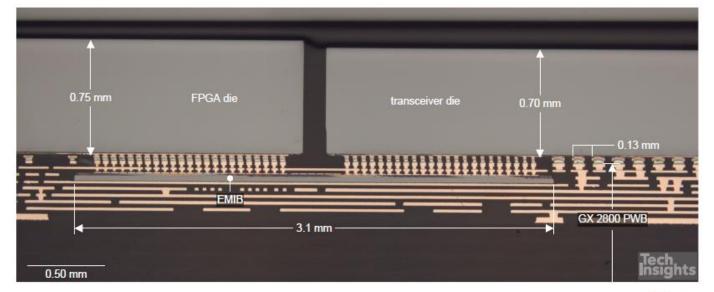


# **Intel's EMIB Package Cross Section**



Source: Intel.

- Embedded Multi-die Interconnect Bridge (EMIB)
   A small silicon bridge chip is embedded into the package (no TSVs)
  - Package substrate provided by substrate supplier (does Si bridge embedding)
  - Micro bumps on chips, communication between chips through bridge in interposer
  - provides a 2.5D localized high-density interconnect between the FPGA and the transceiver die



Intel.Stratix-10

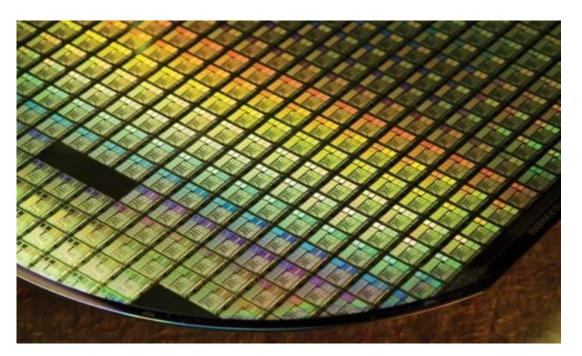
Source: TechInsights



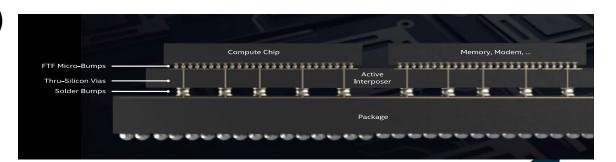
## **3D Integration**

#### More 3D memory stacking

- HBM2 in production today at Samsung and SK Hynix
- HBM from Micron sampling
- Intel's Foveros
  - Micro bump in first production
  - Future hybrid bonding
- TSMC's SoIC and WoW
  - System on Integrated Chip (SoIC) 3D stack using CoW process to handle <10μm pad pitch between chips
  - Use of hybrid bonding
- New forms of 3D stacking (die-to-die interconnects) are coming
  - Die-to-wafer attach
  - Wafer-to-wafer attach
- Co-design is essential

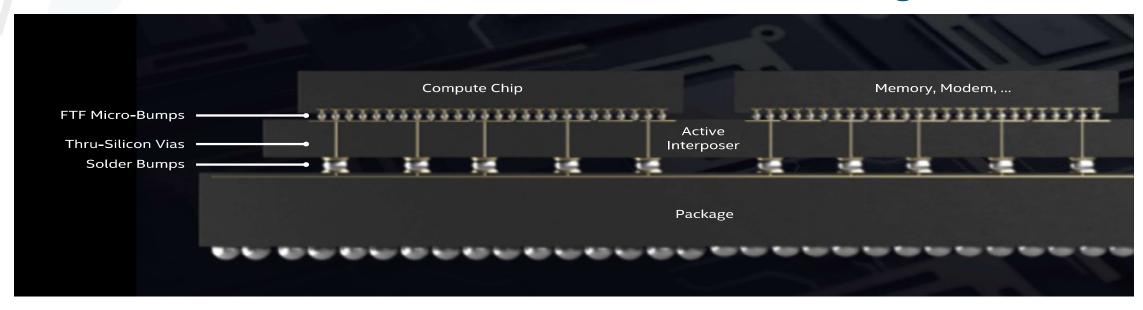


Source: TSMC.



Source: Intel.

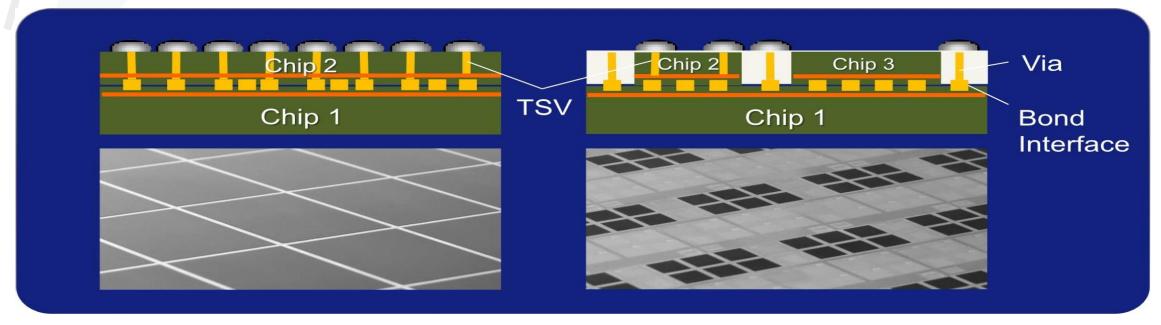
#### **Intel Foveros 3D Face-to-Face Stacking**



Source: Intel.

- Intel's Foveros technology is considered 3D because die are stacked on an active interposer
- Gives designers greater flexibility to mix and match IP blocks with various memory and I/O elements into new form factors
- Mounting memory on active interposer removes the bottleneck of memory proximity
- Technology uses 3D face-to-face stacking process
  - Large die are bumped and mounted on an active interposer next to memory or die with other functions
  - Active interposer can contact platform controller hub (PCH) that manages I/O for the system
  - Active interposer is attached to the package substrate with solder bumps

#### **TSMC SolC™ Technology**

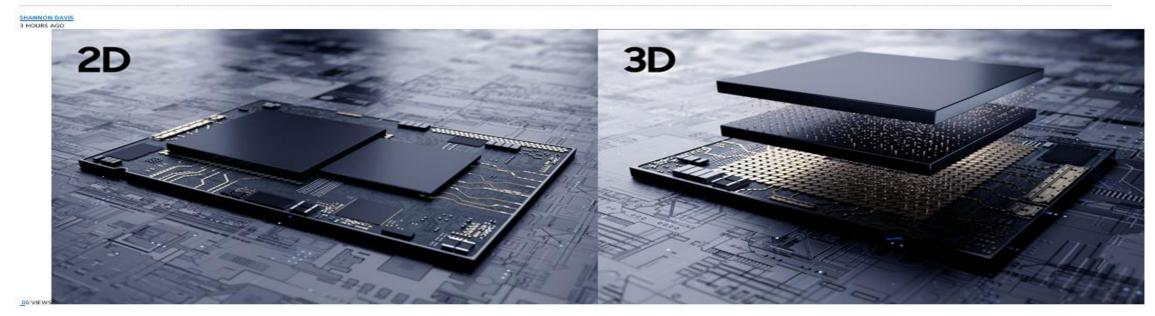


Source: TSMC.

- First commercial products with SoIC expected in 2021, designs in Q4 2020
- Commercial products with up to 10 chiplets expected in 2-3 years
- Advanced silicon nodes of 7nm or 5nm could be used
- Possible to stack III-V components as long as Cu damascene process is applied to wafer
- SoIC could be placed next to HBM on RDL substrate or SoIC could be mounted next to HBM on CoWoS

## Samsung 3D IC Heterogeneous Integration

Samsung Announces Availability of its Silicon-Proven 3D IC Technology for High-Performance Applications



Source: Samsung.

Samsung introduction of logic and memory stack



#### **Test Challenges for Heterogeneous Integration**

- Known Good Die (KGD) required
  - BIST and redundancy
- Known Good Substrate needed
  - AOI used for inspection
- Know Good Interconnect (assumed)
- Need more comprehensive test content that can be run at wafer-level
- Need new methods to probe fine pitch bumps or test coverage without touching µbumps





# Thank you!

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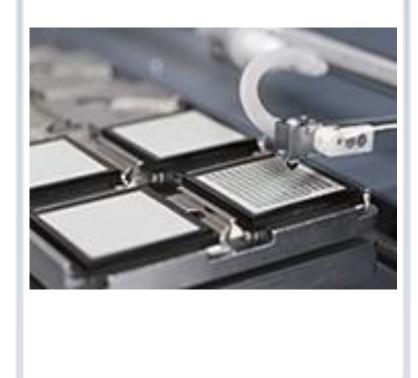
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